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by MC145151–2/D

MC145151-2

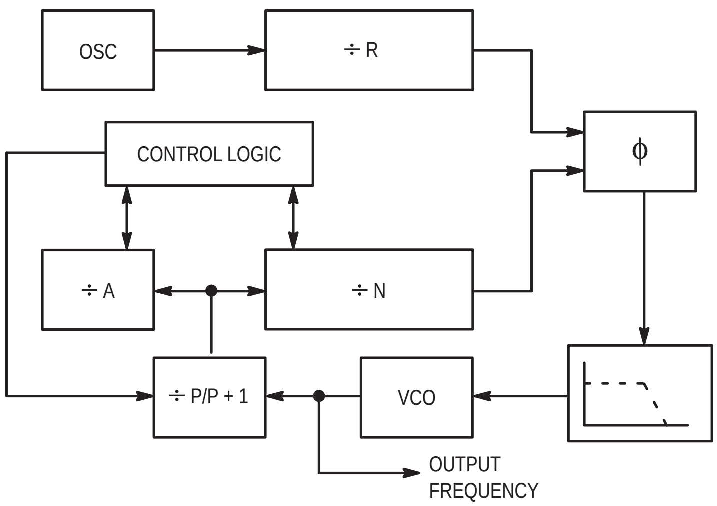
PLL Frequency Synthesizer Family

CMOS

The devices described in this document are typically used as low–power, phase–locked loop frequency synthesizers. When combined with an external low–pass filter and voltage–controlled oscillator, these devices can provide all the remaining functions for a PLL frequency synthesizer operating up to the device's frequency limit. For higher VCO frequency operation, a down mixer or a prescaler can be used between the VCO and the synthesizer IC.

These frequency synthesizer chips can be found in the following and other applications:

CATV	TV Tuning
AM/FM Radios	Scanning Receivers
Two–Way Radios	Amateur Radio



CONTENTS

REV 4
12/99

MC145151-2

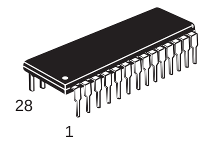
Parallel-Input PLL Frequency Synthesizer

Interfaces with Single–Modulus Prescalers

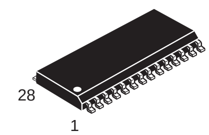
The MC145151–2 is programmed by 14 parallel–input data lines for the N counter and three input lines for the R counter. The device features consist of a reference oscillator, selectable–reference divider, digital–phase detector, and 14–bit programmable divide–by–N counter.

The MC145151–2 is an improved–performance drop–in replacement for the MC145151–1. The power consumption has decreased and ESD and latch–up performance have improved.

- Operating Temperature Range: – 40 to 85°C
- Low Power Consumption Through Use of CMOS Technology
- 3.0 to 9.0 V Supply Range
- On– or Off–Chip Reference Oscillator Operation
- Lock Detect Signal
- ÷ N Counter Output Available
- Single Modulus/Parallel Programming
- 8 User–Selectable ÷ R Values: 8, 128, 256, 512, 1024, 2048, 2410, 8192
- ÷ N Range = 3 to 16383
- “Linearized” Digital Phase Detector Enhances Transfer Function Linearity
- Two Error Signal Options: Single–Ended (Three–State) or Double–Ended
- Chip Complexity: 8000 FETs or 2000 Equivalent Gates



P SUFFIX
PLASTIC DIP
CASE 710



DW SUFFIX
SOG PACKAGE
CASE 751F

ORDERING INFORMATION

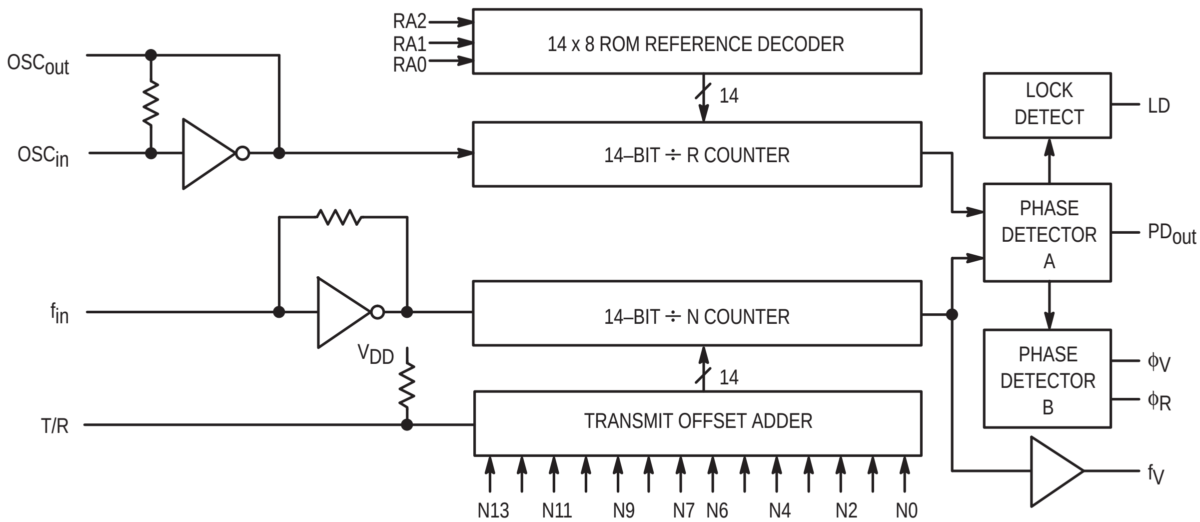
MC145151P2	Plastic DIP
MC145151DW2	SOG Package

PIN ASSIGNMENT

f_{in}	1	28	LD
V_{SS}	2	27	OSC_{in}
V_{DD}	3	26	OSC_{out}
PD_{out}	4	25	N11
RA0	5	24	N10
RA1	6	23	N13
RA2	7	22	N12
ϕ_R	8	21	T/R
ϕ_V	9	20	N9
f_V	10	19	N8
N0	11	18	N7
N1	12	17	N6
N2	13	16	N5
N3	14	15	N4

REV 1
8/95

MC145151–2 BLOCK DIAGRAM



NOTE: N0 – N13 inputs and inputs RA0, RA1, and RA2 have pull–up resistors that are not shown.

PIN DESCRIPTIONS

INPUT PINS

f_{in}
Frequency Input (Pin 1)

Input to the ÷ N portion of the synthesizer. f_{in} is typically derived from loop VCO and is ac coupled into the device. For larger amplitude signals (standard CMOS logic levels) dc coupling may be used.

RA0 – RA2
Reference Address Inputs (Pins 5, 6, 7)

These three inputs establish a code defining one of eight possible divide values for the total reference divider, as defined by the table below.

Pull–up resistors ensure that inputs left open remain at a logic 1 and require only a SPST switch to alter data to the zero state.

Reference Address Code			Total Divide Value
RA2	RA1	RA0	
0	0	0	8
0	0	1	128
0	1	0	256
0	1	1	512
1	0	0	1024
1	0	1	2048
1	1	0	2410
1	1	1	8192

N0 – N11
N Counter Programming Inputs (Pins 11 – 20, 22 – 25)

These inputs provide the data that is preset into the ÷ N counter when it reaches the count of zero. N0 is the least significant and N13 is the most significant. Pull–up resistors ensure that inputs left open remain at a logic 1 and require only an SPST switch to alter data to the zero state.

T/R
Transmit/Receive Offset Adder Input (Pin 21)

This input controls the offset added to the data provided at the N inputs. This is normally used for offsetting the VCO frequency by an amount equal to the IF frequency of the transceiver. This offset is fixed at 856 when T/R is low and gives no offset when T/R is high. A pull–up resistor ensures that no connection will appear as a logic 1 causing no offset addition.

OSC_{in}, OSC_{out}
Reference Oscillator Input/Output (Pins 27, 26)

These pins form an on–chip reference oscillator when connected to terminals of an external parallel resonant crystal. Frequency setting capacitors of appropriate value must be connected from OSC_{in} to ground and OSC_{out} to ground. OSC_{in} may also serve as the input for an externally–generated reference signal. This signal is typically ac coupled to OSC_{in}, but for larger amplitude signals (standard CMOS logic levels) dc coupling may also be used. In the external reference mode, no connection is required to OSC_{out}.

OUTPUT PINS

PD_{out}
Phase Detector A Output (Pin 4)

Three–state output of phase detector for use as loop–error signal. Double–ended outputs are also available for this purpose (see ϕ_V and ϕ_R).

Frequency $f_V > f_R$ or f_V Leading: Negative Pulses
Frequency $f_V < f_R$ or f_V Lagging: Positive Pulses
Frequency $f_V = f_R$ and Phase Coincidence: High–Impedance State

ϕ_R, ϕ_V
Phase Detector B Outputs (Pins 8, 9)

These phase detector outputs can be combined externally for a loop–error signal. A single–ended output is also available for this purpose (see **PD$_{out}$**).

If frequency f_V is greater than f_R or if the phase of f_V is leading, then error information is provided by ϕ_V pulsing low. ϕ_R remains essentially high.

If the frequency f_V is less than f_R or if the phase of f_V is lagging, then error information is provided by ϕ_R pulsing low. ϕ_V remains essentially high.

If the frequency of $f_V = f_R$ and both are in phase, then both ϕ_V and ϕ_R remain high except for a small minimum time period when both pulse low in phase.

f_V
N Counter Output (Pin 10)

This is the buffered output of the ÷ N counter that is internally connected to the phase detector input. With this output available, the ÷ N counter can be used independently.

LD
Lock Detector Output (Pin 28)

Essentially a high level when loop is locked (f_R, f_V of same phase and frequency). Pulses low when loop is out of lock.

POWER SUPPLY

V_{DD}
Positive Power Supply (Pin 3)

The positive power supply potential. This pin may range from + 3 to + 9 V with respect to V_{SS}.

V_{SS}
Negative Power Supply (Pin 2)

The most negative supply potential. This pin is usually ground.

TYPICAL APPLICATIONS

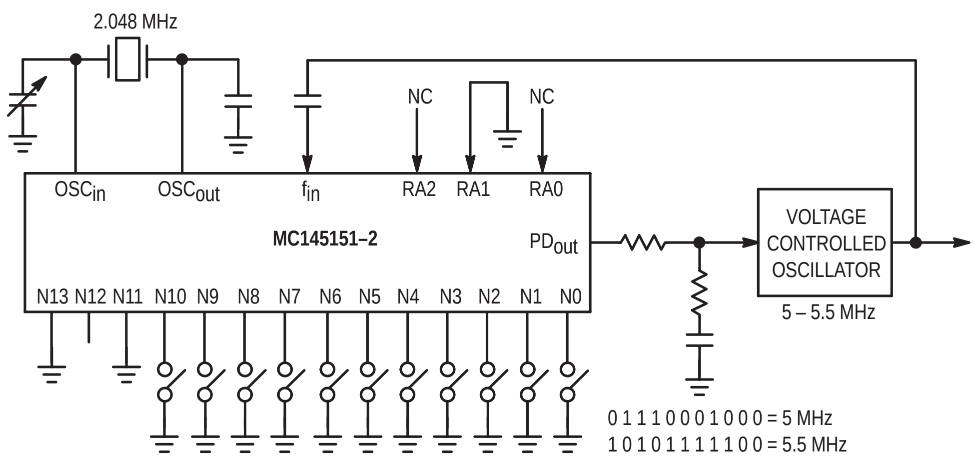
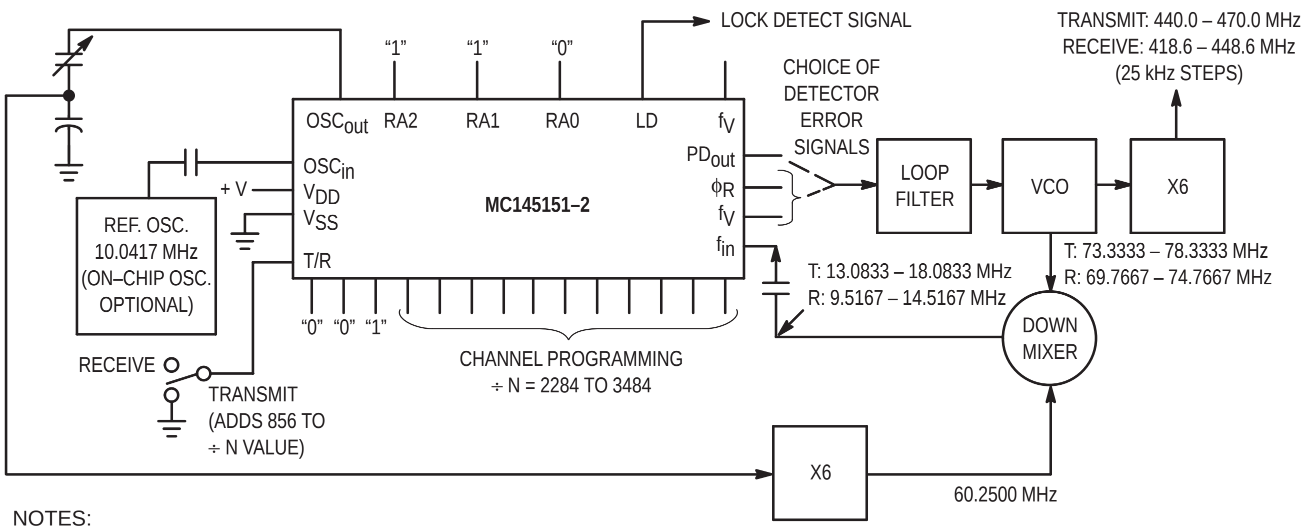


Figure 1. 5 MHz to 5.5 MHz Local Oscillator Channel Spacing = 1 kHz



NOTES:
1. f_R = 4.1667 kHz; ÷ R = 2410; 21.4 MHz low side injection during receive.
2. Frequency values shown are for the 440 – 470 MHz band. Similar implementation applies to the 406 – 440 MHz band. For 470 – 512 MHz, consider reference oscillator frequency X9 for mixer injection signal (90.3750 MHz).

Figure 2. Synthesizer for Land Mobile Radio UHF Bands

MC145151–2 Data Sheet Continued on Page 15

MC14515X–2 FAMILY CHARACTERISTICS AND DESCRIPTIONS

MAXIMUM RATINGS* (Voltages Referenced to V_{SS})

Symbol	Parameter	Value	Unit
V_{DD}	DC Supply Voltage	– 0.5 to + 10.0	V
V_{in}, V_{out}	Input or Output Voltage (DC or Transient) except SW1, SW2	– 0.5 to V_{DD} + 0.5	V
V_{out}	Output Voltage (DC or Transient), SW1, SW2 ($R_{pull–up}$ = 4.7 kΩ)	– 0.5 to + 15	V
I_{in}, I_{out}	Input or Output Current (DC or Transient), per Pin	± 10	mA
I_{DD}, I_{SS}	Supply Current, V_{DD} or V_{SS} Pins	± 30	mA
P_D	Power Dissipation, per Package†	500	mW
T_{stg}	Storage Temperature	– 65 to + 150	°C
T_L	Lead Temperature, 1 mm from Case for 10 seconds	260	°C

* Maximum Ratings are those values beyond which damage to the device may occur. Functional operation should be restricted to the limits in the Electrical Characteristics tables or Pin Descriptions section.

† Power Dissipation Temperature Derating:
Plastic DIP: – 12 mW/°C from 65 to 85°C
SOG Package: – 7 mW/°C from 65 to 85°C

These devices contain protection circuitry to protect against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to these high–impedance circuits. For proper operation, V_{in} and V_{out} should be constrained to the range $V_{SS} \leq (V_{in}$ or $V_{out}) \leq V_{DD}$ except for SW1 and SW2.

SW1 and SW2 can be tied through external resistors to voltages as high as 15 V, independent of the supply voltage.

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either V_{SS} or V_{DD}), except for inputs with pull–up devices. Unused outputs must be left open.

ELECTRICAL CHARACTERISTICS (Voltages Referenced to V_{SS})

Symbol	Parameter	Test Condition	V_{DD} V	– 40°C Min	– 40°C Max	25°C Min	25°C Max	85°C Min	85°C Max	Unit
V_{DD}	Power Supply Voltage Range		—	3	9	3	9	3	9	V
I_{SS}	Dynamic Supply Current	f_{in} = OSC_{in} = 10 MHz, 1 V p–p ac coupled sine wave R = 128, A = 32, N = 128	3 5 9	— — —	3.5 10 30	— — —	3 7.5 24	— — —	3 7.5 24	mA
I_{SS}	Quiescent Supply Current (not including pull–up current component)	V_{in} = V_{DD} or V_{SS} I_{out} = 0 µA	3 5 9	— — —	800 1200 1600	— — —	800 1200 1600	— — —	1600 2400 3200	µA
V_{in}	Input Voltage — f_{in}, OSC_{in}	Input ac coupled sine wave	—	500	—	500	—	500	—	mV p–p
V_{IL}	Low–Level Input Voltage — f_{in}, OSC_{in}	$V_{out} \geq$ 2.1 V Input dc $V_{out} \geq$ 3.5 V coupled $V_{out} \geq$ 6.3 V square wave	3 5 9	— — —	0 0 0	— — —	0 0 0	— — —	0 0 0	V
V_{IH}	High–Level Input Voltage — f_{in}, OSC_{in}	$V_{out} \leq$ 0.9 V Input dc $V_{out} \leq$ 1.5 V coupled $V_{out} \leq$ 2.7 V square wave	3 5 9	3.0 5.0 9.0	— — —	3.0 5.0 9.0	— — —	3.0 5.0 9.0	— — —	V
V_{IL}	Low–Level Input Voltage — except f_{in}, OSC_{in}		3 5 9	— — —	0.9 1.5 2.7	— — —	0.9 1.5 2.7	— — —	0.9 1.5 2.7	V
V_{IH}	High–Level Input Voltage — except f_{in}, OSC_{in}		3 5 9	2.1 3.5 6.3	— — —	2.1 3.5 6.3	— — —	2.1 3.5 6.3	— — —	V
I_{in}	Input Current (f_{in}, OSC_{in})	V_{in} = V_{DD} or V_{SS}	9	± 2	± 50	± 2	± 25	± 2	± 22	µA
I_{IL}	Input Leakage Current (Data, CLK, ENB — without pull–ups)	V_{in} = V_{SS}	9	—	– 0.3	—	– 0.1	—	– 1.0	µA
I_{IH}	Input Leakage Current (all inputs except f_{in}, OSC_{in})	V_{in} = V_{DD}	9	—	0.3	—	0.1	—	1.0	µA

(continued)

DC ELECTRICAL CHARACTERISTICS (continued)

Symbol	Parameter	Test Condition	V_{DD} V	– 40°C		25°C		85°C		Unit
				Min	Max	Min	Max	Min	Max	
I_{IL}	Pull–up Current (all inputs with pull–ups)	$V_{in} = V_{SS}$	9	– 20	– 400	– 20	– 200	– 20	– 170	µA
C_{in}	Input Capacitance		—	—	10	—	10	—	10	pF
V_{OL}	Low–Level Output Voltage — OSC_{out}	$I_{out} \approx 0$ µA $V_{in} = V_{DD}$	3 5 9	— — —	0.9 1.5 2.7	— — —	0.9 1.5 2.7	— — —	0.9 1.5 2.7	V
V_{OH}	High–Level Output Voltage — OSC_{out}	$I_{out} \approx 0$ µA $V_{in} = V_{SS}$	3 5 9	2.1 3.5 6.3	— — —	2.1 3.5 6.3	— — —	2.1 3.5 6.3	— — —	V
V_{OL}	Low–Level Output Voltage — Other Outputs	$I_{out} \approx 0$ µA	3 5 9	— — —	0.05 0.05 0.05	— — —	0.05 0.05 0.05	— — —	0.05 0.05 0.05	V
V_{OH}	High–Level Output Voltage — Other Outputs	$I_{out} \approx 0$ µA	3 5 9	2.95 4.95 8.95	— — —	2.95 4.95 8.95	— — —	2.95 4.95 8.95	— — —	V
$V_{(BR)DSS}$	Drain–to–Source Breakdown Voltage — SW1, SW2	$R_{pull–up}$ = 4.7 kΩ	—	15	—	15	—	15	—	V
I_{OL}	Low–Level Sinking Current — MC	V_{out} = 0.3 V V_{out} = 0.4 V V_{out} = 0.5 V	3 5 9	1.30 1.90 3.80	— — —	1.10 1.70 3.30	— — —	0.66 1.08 2.10	— — —	mA
I_{OH}	High–Level Sourcing Current — MC	V_{out} = 2.7 V V_{out} = 4.6 V V_{out} = 8.5 V	3 5 9	– 0.60 – 0.90 – 1.50	— — —	– 0.50 – 0.75 – 1.25	— — —	– 0.30 – 0.50 – 0.80	— — —	mA
I_{OL}	Low–Level Sinking Current — LD	V_{out} = 0.3 V V_{out} = 0.4 V V_{out} = 0.5 V	3 5 9	0.25 0.64 1.30	— — —	0.20 0.51 1.00	— — —	0.15 0.36 0.70	— — —	mA
I_{OH}	High–Level Sourcing Current — LD	V_{out} = 2.7 V V_{out} = 4.6 V V_{out} = 8.5 V	3 5 9	– 0.25 – 0.64 – 1.30	— — —	– 0.20 – 0.51 – 1.00	— — —	– 0.15 – 0.36 – 0.70	— — —	mA
I_{OL}	Low–Level Sinking Current — SW1, SW2	V_{out} = 0.3 V V_{out} = 0.4 V V_{out} = 0.5 V	3 5 9	0.80 1.50 3.50	— — —	0.48 0.90 2.10	— — —	0.24 0.45 1.05	— — —	mA
I_{OL}	Low–Level Sinking Current — Other Outputs	V_{out} = 0.3 V V_{out} = 0.4 V V_{out} = 0.5 V	3 5 9	0.44 0.64 1.30	— — —	0.35 0.51 1.00	— — —	0.22 0.36 0.70	— — —	mA
I_{OH}	High–Level Sourcing Current — Other Outputs	V_{out} = 2.7 V V_{out} = 4.6 V V_{out} = 8.5 V	3 5 9	– 0.44 – 0.64 – 1.30	— — —	– 0.35 – 0.51 – 1.00	— — —	– 0.22 – 0.36 – 0.70	— — —	mA
I_{OZ}	Output Leakage Current — PD_{out}	$V_{out} = V_{DD}$ or V_{SS} Output in Off State	9	—	± 0.3	—	± 0.1	—	± 1.0	µA
I_{OZ}	Output Leakage Current — SW1, SW2	$V_{out} = V_{DD}$ or V_{SS} Output in Off State	9	—	± 0.3	—	± 0.1	—	± 3.0	µA
C_{out}	Output Capacitance — PD_{out}	PD_{out} — Three–State	—	—	10	—	10	—	10	pF

AC ELECTRICAL CHARACTERISTICS (C_L = 50 pF, Input t_r = t_f = 10 ns)

Symbol	Parameter	V_{DD} V	Guaranteed Limit 25°C	Guaranteed Limit – 40 to 85°C	Unit
t_{PLH}, t_{PHL}	Maximum Propagation Delay, f_{in} to MC (Figures 1 and 4)	3 5 9	110 60 35	120 70 40	ns
t_{PHL}	Maximum Propagation Delay, ENB to SW1, SW2 (Figures 1 and 5)	3 5 9	160 80 50	180 95 60	ns
t_w	Output Pulse Width, ϕ_R, ϕ_V, and LD with f_R in Phase with f_V (Figures 2 and 4)	3 5 9	25 to 200 20 to 100 10 to 70	25 to 260 20 to 125 10 to 80	ns
t_{TLH}	Maximum Output Transition Time, MC (Figures 3 and 4)	3 5 9	115 60 40	115 75 60	ns
t_{THL}	Maximum Output Transition Time, MC (Figures 3 and 4)	3 5 9	60 34 30	70 45 38	ns
t_{TLH}, t_{THL}	Maximum Output Transition Time, LD (Figures 3 and 4)	3 5 9	180 90 70	200 120 90	ns
t_{TLH}, t_{THL}	Maximum Output Transition Time, Other Outputs (Figures 3 and 4)	3 5 9	160 80 60	175 100 65	ns

SWITCHING WAVEFORMS

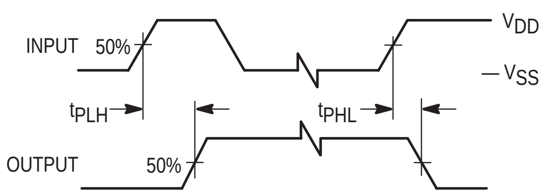
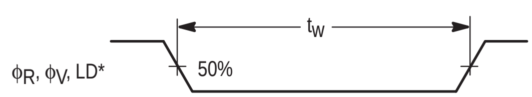


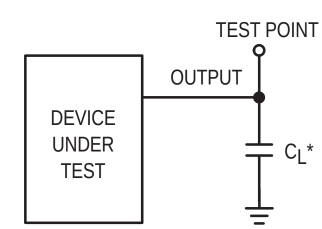
Figure 1.



* f_R in phase with f_V.

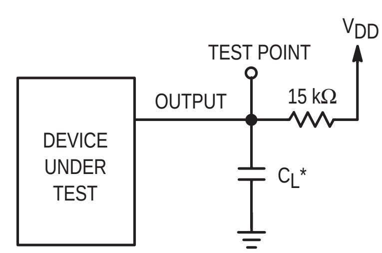
Figure 2.

Figure 3.



* Includes all probe and fixture capacitance.

Figure 4. Test Circuit



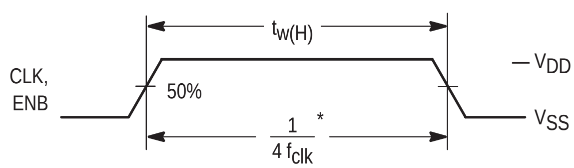
* Includes all probe and fixture capacitance.

Figure 5. Test Circuit

TIMING REQUIREMENTS (Input $t_r = t_f = 10$ ns unless otherwise indicated)

Symbol	Parameter	V_{DD} V	Guaranteed Limit 25°C	Guaranteed Limit – 40 to 85°C	Unit
f_{clk}	Serial Data Clock Frequency, Assuming 25% Duty Cycle NOTE: Refer to CLK $t_{w(H)}$ below (Figure 6)	3 5 9	dc to 5.0 dc to 7.1 dc to 10	dc to 3.5 dc to 7.1 dc to 10	MHz
t_{su}	Minimum Setup Time, Data to CLK (Figure 7)	3 5 9	30 20 18	30 20 18	ns
t_h	Minimum Hold Time, CLK to Data (Figure 7)	3 5 9	40 20 15	40 20 15	ns
t_{su}	Minimum Setup Time, CLK to ENB (Figure 7)	3 5 9	70 32 25	70 32 25	ns
t_{rec}	Minimum Recovery Time, ENB to CLK (Figure 7)	3 5 9	5 10 20	5 10 20	ns
$t_{w(H)}$	Minimum Pulse Width, CLK and ENB (Figure 6)	3 5 9	50 35 25	70 35 25	ns
t_r, t_f	Maximum Input Rise and Fall Times — Any Input (Figure 8)	3 5 9	5 4 2	5 4 2	µs

SWITCHING WAVEFORMS



*Assumes 25% Duty Cycle.

Figure 6.

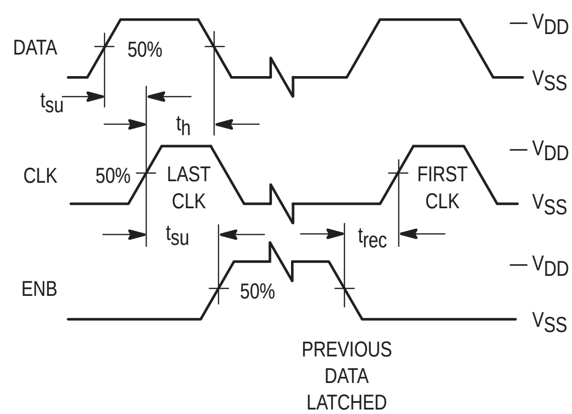


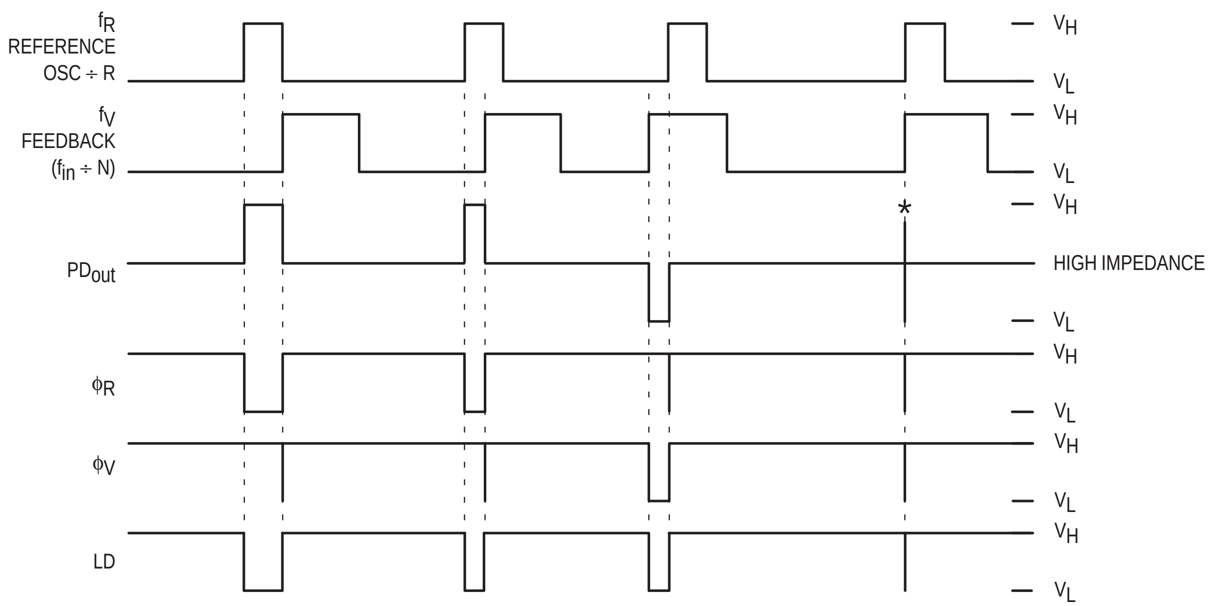
Figure 7.

Figure 8.

FREQUENCY CHARACTERISTICS (Voltages References to V_{SS}, C_L = 50 pF, Input t_r = t_f =10 ns unless otherwise indicated)

Symbol	Parameter	Test Condition	V_{DD} V	– 40°C Min	– 40°C Max	25°C Min	25°C Max	85°C Min	85°C Max	Unit
f_i	Input Frequency (f_{in}, OSC_{in})	R ≥ 8, A ≥ 0, N ≥ 8 V_{in} = 500 mV p–p ac coupled sine wave	3 5 9	— — —	6 15 15	— — —	6 15 15	— — —	6 15 15	MHz
		R ≥ 8, A ≥ 0, N ≥ 8 V_{in} = 1 V p–p ac coupled sine wave	3 5 9	— — —	12 22 25	— — —	12 20 22	— — —	7 20 22	MHz
		R ≥ 8, A ≥ 0, N ≥ 8 V_{in} = V_{DD} to V_{SS} dc coupled square wave	3 5 9	— — —	13 25 25	— — —	12 22 25	— — —	8 22 25	MHz

NOTE: Usually, the PLL's propagation delay from f_{in} to MC plus the setup time of the prescaler determines the upper frequency limit of the system. The upper frequency limit is found with the following formula: $f = P / (t_P + t_{set})$ where f is the upper frequency in Hz, P is the lower of the dual modulus prescaler ratios, t_P is the f_{in} to MC propagation delay in seconds, and t_{set} is the prescaler setup time in seconds.
For example, with a 5 V supply, the f_{in} to MC delay is 70 ns. If the MC12028A prescaler is used, the setup time is 16 ns. Thus, if the 64/65 ratio is utilized, the upper frequency limit is $f = P / (t_P + t_{set})$ = 64/(70 + 16) = 744 MHz.



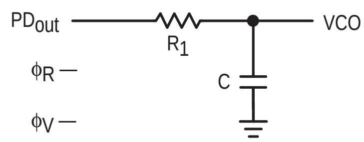
V_H = High Voltage Level.
V_L = Low Voltage Level.
* At this point, when both f_R and f_V are in phase, the output is forced to near mid–supply.
NOTE: The PD_{out} generates error pulses during out–of–lock conditions. When locked in phase and frequency the output is high and the voltage at this pin is determined by the low–pass filter capacitor.

Figure 9. Phase Detector/Lock Detector Output Waveforms

DESIGN CONSIDERATIONS

PHASE–LOCKED LOOP — LOW–PASS FILTER DESIGN

A)

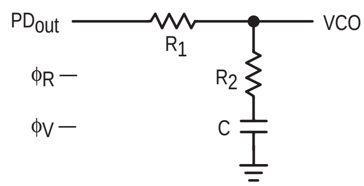


$$\omega_n = \sqrt{\frac{K_\phi K_{VCO}}{NR_1C}}$$

$$\zeta = \frac{N\omega_n}{2K_\phi K_{VCO}}$$

$$F(s) = \frac{1}{R_1sC + 1}$$

B)

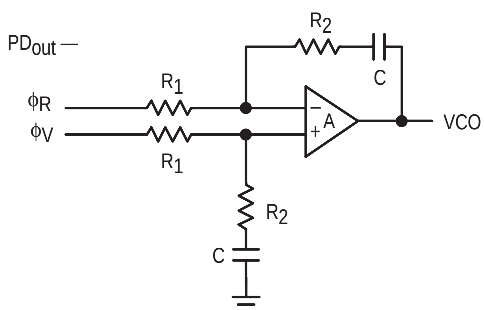


$$\omega_n = \sqrt{\frac{K_\phi K_{VCO}}{NC(R_1 + R_2)}}$$

$$\zeta = 0.5\,\omega_n \left(R_2C + \frac{N}{K_\phi K_{VCO}}\right)$$

$$F(s) = \frac{R_2sC + 1}{(R_1 + R_2)sC + 1}$$

C)



$$\omega_n = \sqrt{\frac{K_\phi K_{VCO}}{NCR_1}}$$

$$\zeta = \frac{\omega_n R_2 C}{2}$$

ASSUMING GAIN A IS VERY LARGE, THEN:

$$F(s) = \frac{R_2sC + 1}{R_1sC}$$

NOTE: Sometimes R_1 is split into two series resistors, each $R_1 \div 2$. A capacitor C_C is then placed from the midpoint to ground to further filter ϕ_V and ϕ_R. The value of C_C should be such that the corner frequency of this network does not significantly affect ω_n.
The ϕ_R and ϕ_V outputs swing rail–to–rail. Therefore, the user should be careful not to exceed the common mode input range of the op amp used in the combiner/loop filter.

DEFINITIONS:
N = Total Division Ratio in feedback loop
K_ϕ (Phase Detector Gain) = $V_{DD}/4\pi$ for PD_{out}
K_ϕ (Phase Detector Gain) = $V_{DD}/2\pi$ for ϕ_V and ϕ_R
K_{VCO} (VCO Gain) = $\frac{2\pi\Delta f_{VCO}}{\Delta V_{VCO}}$
for a typical design w_n (Natural Frequency) $\approx \frac{2\pi fr}{10}$ (at phase detector input).
Damping Factor: $\zeta \cong 1$

RECOMMENDED READING:

Gardner, Floyd M., *Phaselock Techniques (second edition).* New York, Wiley–Interscience, 1979.
Manassewitsch, Vadim, *Frequency Synthesizers: Theory and Design (second edition).* New York, Wiley–Interscience, 1980.
Blanchard, Alain, *Phase–Locked Loops: Application to Coherent Receiver Design.* New York, Wiley–Interscience, 1976.
Egan, William F., *Frequency Synthesis by Phase Lock.* New York, Wiley–Interscience, 1981.
Rohde, Ulrich L., *Digital PLL Frequency Synthesizers Theory and Design.* Englewood Cliffs, NJ, Prentice–Hall, 1983.
Berlin, Howard M., *Design of Phase–Locked Loop Circuits, with Experiments.* Indianapolis, Howard W. Sams and Co., 1978.
Kinley, Harold, *The PLL Synthesizer Cookbook.* Blue Ridge Summit, PA, Tab Books, 1980.
AN535, Phase–Locked Loop Design Fundamentals, Motorola Semiconductor Products, Inc., 1970.
AR254, Phase–Locked Loop Design Articles, Motorola Semiconductor Products, Inc., Reprinted with permission from *Electronic Design,* 1987.

CRYSTAL OSCILLATOR CONSIDERATIONS

The following options may be considered to provide a reference frequency to Motorola's CMOS frequency synthesizers.

Use of a Hybrid Crystal Oscillator

Commercially available temperature–compensated crystal oscillators (TCXOs) or crystal–controlled data clock oscillators provide very stable reference frequencies. An oscillator capable of sinking and sourcing 50 µA at CMOS logic levels may be direct or dc coupled to OSC_{in}. In general, the highest frequency capability is obtained utilizing a direct–coupled square wave having a rail–to–rail (V_{DD} to V_{SS}) voltage swing. If the oscillator does not have CMOS logic levels on the outputs, capacitive or ac coupling to OSC_{in} may be used. OSC_{out}, an unbuffered output, should be left floating.

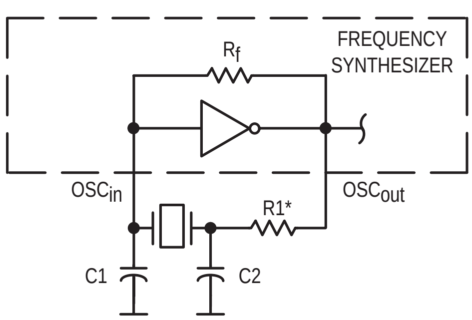
For additional information about TCXOs and data clock oscillators, please consult the latest version of the *eem Electronic Engineers Master Catalog,* the *Gold Book,* or similar publications.

Design an Off–Chip Reference

The user may design an off–chip crystal oscillator using ICs specifically developed for crystal oscillator applications, such as the MC12061 MECL device. The reference signal from the MECL device is ac coupled to OSC_{in}. For large amplitude signals (standard CMOS logic levels), dc coupling is used. OSC_{out}, an unbuffered output, should be left floating. In general, the highest frequency capability is obtained with a direct–coupled square wave having rail–to–rail voltage swing.

Use of the On–Chip Oscillator Circuitry

The on–chip amplifier (a digital inverter) along with an appropriate crystal may be used to provide a reference source frequency. A fundamental mode crystal, parallel resonant at the desired operating frequency, should be connected as shown in Figure 10.



* May be deleted in certain cases. See text.

Figure 10. Pierce Crystal Oscillator Circuit

For V_{DD} = 5.0 V, the crystal should be specified for a loading capacitance, C_L, which does not exceed 32 pF for frequencies to approximately 8.0 MHz, 20 pF for frequencies in the area of 8.0 to 15 MHz, and 10 pF for higher frequencies. These are guidelines that provide a reasonable compromise between IC capacitance, drive capability, swamping variations in stray and IC input/output capacitance, and realistic C_L values. The shunt load capacitance, C_L, presented across the crystal can be estimated to be:

$$C_L = \frac{C_{in}C_{out}}{C_{in} + C_{out}} + C_a + C_o + \frac{C1 \bullet C2}{C1 + C2}$$

where

C_{in} = 5 pF (see Figure 11)
C_{out} = 6 pF (see Figure 11)
C_a = 1 pF (see Figure 11)
C_O = the crystal's holder capacitance (see Figure 12)
C1 and C2 = external capacitors (see Figure 10)

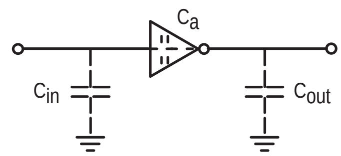
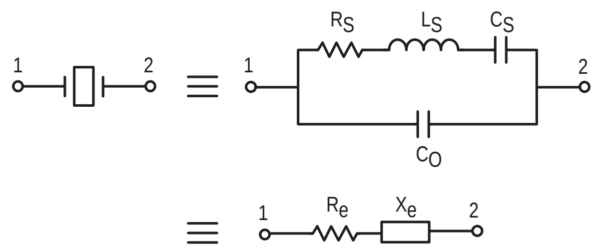


Figure 11. Parasitic Capacitances of the Amplifier



NOTE: Values are supplied by crystal manufacturer (parallel resonant crystal).

Figure 12. Equivalent Crystal Networks

The oscillator can be "trimmed" on–frequency by making a portion or all of C1 variable. The crystal and associated components must be located as close as possible to the OSC_{in} and OSC_{out} pins to minimize distortion, stray capacitance, stray inductance, and startup stabilization time. In some cases, stray capacitance should be added to the value for C_{in} and C_{out}.

Power is dissipated in the effective series resistance of the crystal, R_e, in Figure 12. The drive level specified by the crystal manufacturer is the maximum stress that a crystal can withstand without damage or excessive shift in frequency. R1 in Figure 10 limits the drive level. The use of R1 may not be necessary in some cases (i.e., R1 = 0 Ω).

To verify that the maximum dc supply voltage does not overdrive the crystal, monitor the output frequency as a function of voltage at OSC_{out}. (Care should be taken to minimize loading.) The frequency should increase very slightly as the dc supply voltage is increased. An overdriven crystal will decrease in frequency or become unstable with an increase in supply voltage. The operating supply voltage must be reduced or R1 must be increased in value if the overdriven condition exists. The user should note that the oscillator start–up time is proportional to the value of R1.

Through the process of supplying crystals for use with CMOS inverters, many crystal manufacturers have developed expertise in CMOS oscillator design with crystals. Discussions with such manufacturers can prove very helpful (see Table 1).

Table 1. Partial List of Crystal Manufacturers

Motorola — Internet Address *http://motorola.com* (Search for resonators)
United States Crystal Corp.
Crystek Crystal
Statek Corp.
Fox Electronics

NOTE: Motorola cannot recommend one supplier over another and in no way suggests that this is a complete listing of crystal manufacturers.

RECOMMENDED READING

Technical Note TN–24, Statek Corp.

Technical Note TN–7, Statek Corp.

E. Hafner, "The Piezoelectric Crystal Unit – Definitions and Method of Measurement", *Proc. IEEE,* Vol. 57, No. 2 Feb., 1969.

D. Kemper, L. Rosine, "Quartz Crystals for Frequency Control", *Electro–Technology*, June, 1969.

P. J. Ottowitz, "A Guide to Crystal Selection", *Electronic Design*, May, 1966.

DUAL–MODULUS PRESCALING

OVERVIEW

The technique of dual–modulus prescaling is well established as a method of achieving high performance frequency synthesizer operation at high frequencies. Basically, the approach allows relatively low–frequency programmable counters to be used as high–frequency programmable counters with speed capability of several hundred MHz. This is possible without the sacrifice in system resolution and performance that results if a fixed (single–modulus) divider is used for the prescaler.

In dual–modulus prescaling, the lower speed counters must be uniquely configured. Special control logic is necessary to select the divide value P or P + 1 in the prescaler for the required amount of time (see modulus control definition). Motorola's dual–modulus frequency synthesizers contain this feature and can be used with a variety of dual–modulus prescalers to allow speed, complexity and cost to be tailored to the system requirements. Prescalers having P, P + 1 divide values in the range of ÷ 3/÷ 4 to ÷ 128/÷ 129 can be controlled by most Motorola frequency synthesizers.

Several dual–modulus prescaler approaches suitable for use with the MC145152–2, MC145156–2, or MC145158–2 are:

MC12009	÷ 5/÷ 6	440 MHz
MC12011	÷ 8/÷ 9	500 MHz
MC12013	÷ 10/÷ 11	500 MHz
MC12015	÷ 32/÷ 33	225 MHz
MC12016	÷ 40/÷ 41	225 MHz
MC12017	÷ 64/÷ 65	225 MHz
MC12018	÷ 128/÷ 129	520 MHz
MC12028A	÷ 32/33 or ÷ 64/65	1.1 GHz
MC12052A	÷ 64/65 or ÷ 128/129	1.1 GHz
MC12054A	÷ 64/65 or ÷ 128/129	2.0 GHz

DESIGN GUIDELINES

The system total divide value, N_{total} (N_T) will be dictated by the application:

$$N_T = \frac{\text{frequency into the prescaler}}{\text{frequency into the phase detector}} = N \bullet P + A$$

N is the number programmed into the ÷ N counter, A is the number programmed into the ÷ A counter, P and P + 1 are the two selectable divide ratios available in the dual–modulus prescalers. To have a range of N_T values in sequence, the ÷ A counter is programmed from zero through P – 1 for a particular value N in the ÷ N counter. N is then incremented to N + 1 and the ÷ A is sequenced from 0 through P – 1 again.

There are minimum and maximum values that can be achieved for N_T. These values are a function of P and the size of the ÷ N and ÷ A counters.

The constraint N ≥ A always applies. If A_{max} = P – 1, then N_{min} ≥ P – 1. Then N_{Tmin} = (P – 1) P + A or (P – 1) P since A is free to assume the value of 0.

$$N_{Tmax} = N_{max} \bullet P + A_{max}$$

To maximize system frequency capability, the dual–modulus prescaler output must go from low to high after each group of P or P + 1 input cycles. The prescaler should divide by P when its modulus control line is high and by P + 1 when its MC is low.

For the maximum frequency into the prescaler (f_{VCOmax}), the value used for P must be large enough such that:

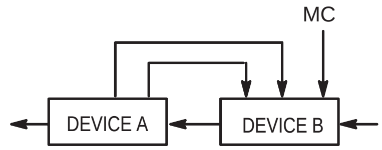
1. f_{VCOmax} divided by P may not exceed the frequency capability of f_{in} (input to the ÷ N and ÷ A counters).
2. The period of f_{VCO} divided by P must be greater than the sum of the times:
   a. Propagation delay through the dual–modulus prescaler.
   b. Prescaler setup or release time relative to its MC signal.
   c. Propagation time from f_{in} to the MC output for the frequency synthesizer device.

A sometimes useful simplification in the programming code can be achieved by choosing the values for P of 8, 16, 32, or 64. For these cases, the desired value of N_T results when N_T in binary is used as the program code to the ÷ N and ÷ A counters treated in the following manner:

1. Assume the ÷ A counter contains "a" bits where 2^a ≥ P.
2. Always program all higher order ÷ A counter bits above "a" to 0.

3. Assume the ÷ N counter and the ÷ A counter (with all the higher order bits above “a” ignored) combined into a single binary counter of n + a bits in length (n = number of divider stages in the ÷ N counter). The MSB of this “hypothetical” counter is to correspond to the MSB of ÷ N and the LSB is to correspond to the LSB of ÷ A. The system divide value, N_T, now results when the value of N_T in binary is used to program the “new” n + a bit counter.

By using the two devices, several dual–modulus values are achievable (shown in Figure 13).



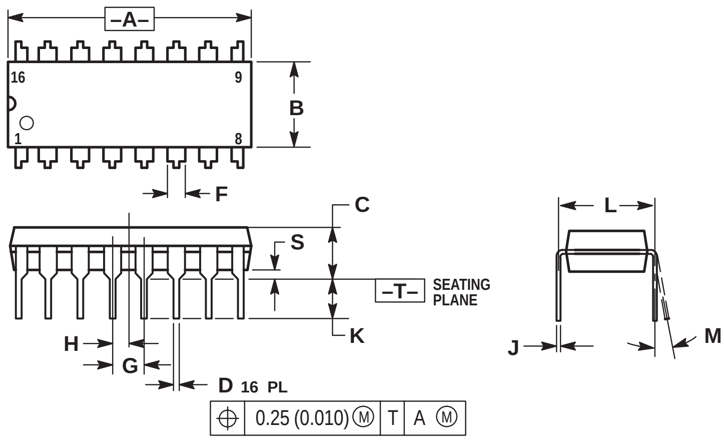
DEVICE A \ DEVICE B	MC12009	MC12011	MC12013
MC10131	÷ 20/÷ 21	÷ 32/÷ 33	÷ 40/÷ 41
MC10138	÷ 50/÷ 51	÷ 80/÷ 81	÷ 100/÷ 101

NOTE: MC12009, MC12011, and MC12013 are pin equivalent.
MC12015, MC12016, and MC12017 are pin equivalent.

Figure 13. Dual–Modulus Values

PACKAGE DIMENSIONS

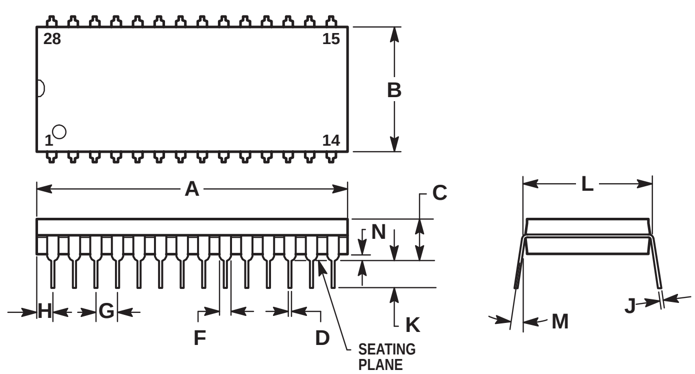
P SUFFIX
PLASTIC DIP
CASE 648–08
(MC145157–2, MC145158–D)



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH.
3. DIMENSION L TO CENTER OF LEADS WHEN FORMED PARALLEL.
4. DIMENSION B DOES NOT INCLUDE MOLD FLASH.
5. ROUNDED CORNERS OPTIONAL.

	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
A	0.740	0.770	18.80	19.55
B	0.250	0.270	6.35	6.85
C	0.145	0.175	3.69	4.44
D	0.015	0.021	0.39	0.53
F	0.040	0.70	1.02	1.77
G	0.100 BSC		2.54 BSC	
H	0.050 BSC		1.27 BSC	
J	0.008	0.015	0.21	0.38
K	0.110	0.130	2.80	3.30
L	0.295	0.305	7.50	7.74
M	0°	10°	0°	10°
S	0.020	0.040	0.51	1.01

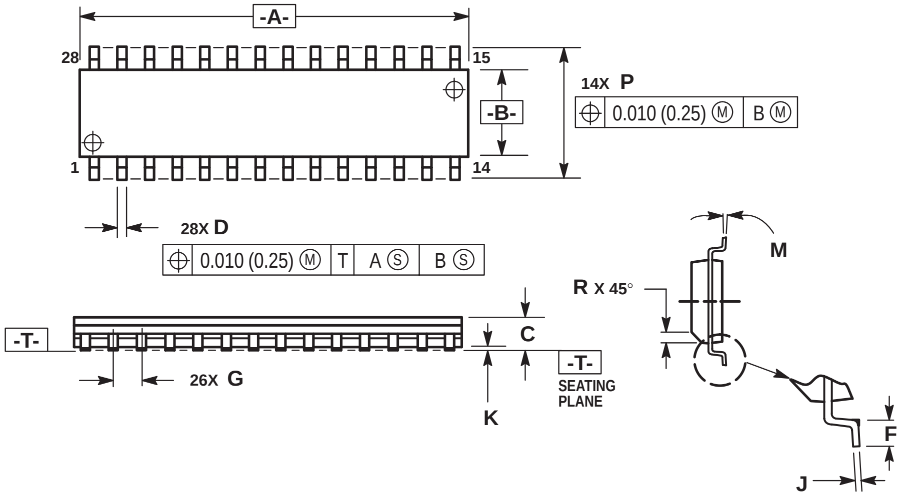
P SUFFIX
PLASTIC DIP
CASE 710–02
(MC145151–2, MC145152–2)



NOTES:
1. POSITIONAL TOLERANCE OF LEADS (D), SHALL BE WITHIN 0.25mm (0.010) AT MAXIMUM MATERIAL CONDITION, IN RELATION TO SEATING PLANE AND EACH OTHER.
2. DIMENSION L TO CENTER OF LEADS WHEN FORMED PARALLEL.
3. DIMENSION B DOES NOT INCLUDE MOLD FLASH.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
A	36.45	37.21	1.435	1.465
B	13.72	14.22	0.540	0.560
C	3.94	5.08	0.155	0.200
D	0.36	0.56	0.014	0.022
F	1.02	1.52	0.040	0.060
G	2.54 BSC		0.100 BSC	
H	1.65	2.16	0.065	0.085
J	0.20	0.38	0.008	0.015
K	2.92	3.43	0.115	0.135
L	15.24 BSC		0.600 BSC	
M	0°	15°	0°	15°
N	0.51	1.02	0.020	0.040

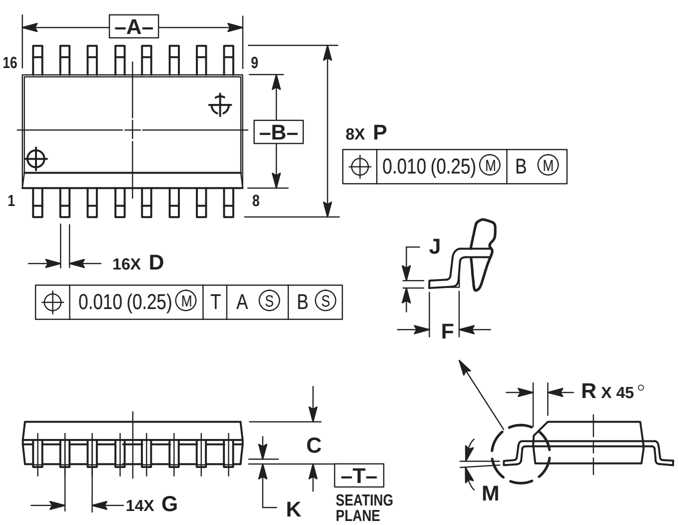
DW SUFFIX
SOG PACKAGE
CASE 751F–04
(MC145151–2, MC145152–2)



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
5. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.13 (0.005) TOTAL IN EXCESS OF D DIMENSION AT MAXIMUM MATERIAL CONDITION.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
A	17.80	18.05	0.701	0.711
B	7.40	7.60	0.292	0.299
C	2.35	2.65	0.093	0.104
D	0.35	0.49	0.014	0.019
F	0.41	0.90	0.016	0.035
G	1.27 BSC		0.050 BSC	
J	0.23	0.32	0.009	0.013
K	0.13	0.29	0.005	0.011
M	0°	8°	0°	8°
P	10.05	10.55	0.395	0.415
R	0.25	0.75	0.010	0.029

DW SUFFIX
SOG PACKAGE
CASE 751G–02
(MC145157–2, MC145158–2)



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION.
4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
5. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.13 (0.005) TOTAL IN EXCESS OF D DIMENSION AT MAXIMUM MATERIAL CONDITION.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
A	10.15	10.45	0.400	0.411
B	7.40	7.60	0.292	0.299
C	2.35	2.65	0.093	0.104
D	0.35	0.49	0.014	0.019
F	0.50	0.90	0.020	0.035
G	1.27 BSC		0.050 BSC	
J	0.25	0.32	0.010	0.012
K	0.10	0.25	0.004	0.009
M	0°	7°	0°	7°
P	10.05	10.55	0.395	0.415
R	0.25	0.75	0.010	0.029

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